



**MICROCHIP**

## **QUALIFICATION PLAN**

**PCN #: JAON-01XOEE717**

**Date:  
Mar 25, 2015**

**Qualification of palladium coated copper with gold flash  
(PdCuAu) bond wire in selected products of the 160K wafer  
technology available in 8L SOIC package at MTAI assembly  
site**

Distribution

Surasit P.  
Wanphen L.  
Wichai K.  
Fernando C.  
Chalermpon P.

Rangsun K.  
A. Navarro  
Chaweng W.  
Oliver B.

Microchip Technology (Thailand) Co., Ltd.  
14 Moo 1 T. Wangtakien A. Muangchacherngsao,  
Chacherngsao, Thailand, 24000  
Tel. (6638) 857119-45, 857311-19 ext. 1231  
Fax (6638) 857149-50

**Purpose:** \_\_\_\_\_ Qualification of palladium coated copper with gold flash (PdCuAu) bond wire in selected products of the 160K wafer technology available in 8L SOIC package at MTAI assembly site

**MP code:** \_\_\_\_\_ DFAW1

**Part No.:** \_\_\_\_\_ 24AA01/24LC01B

**BD No:** \_\_\_\_\_ BDM-000645 rev.A

**CCB No.:** \_\_\_\_\_ 1563

**Package:**

**Type** \_\_\_\_\_ 8L SOIC

**Width or Size** \_\_\_\_\_ 150 mils

**Die thickness:** \_\_\_\_\_ 15 mils

**Die size:** \_\_\_\_\_ 28.3 x 29.3 mils

**Lead frame:**

**Paddle size:** \_\_\_\_\_ 90 x 90 mils

**Material** \_\_\_\_\_ CDA194

**Surface** \_\_\_\_\_ Bare copper on paddle

**Process** \_\_\_\_\_ Stamp

**Lead Lock** \_\_\_\_\_ No

**Part Number** \_\_\_\_\_ 10100812

**Treatment** \_\_\_\_\_ Brown Oxide Treatment

**Wire:**

**Material** \_\_\_\_\_ PdCu-Au flash

**Die Attach Epoxy:**

**Part Number** \_\_\_\_\_ 8390A

**Conductive** \_\_\_\_\_ Yes

**Mold Compound:** \_\_\_\_\_ G600V

**Lead finish** \_\_\_\_\_ Matte tin

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	1	5	0 fails after TC	5	30 bonds from a minimum of 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	1	5	0	5	30 bonds from a minimum of 5 devices.
HTSL (High Temp Storage Life)	+175 C for 504 hours or 150°C for 1008 hrs. Electrical test pre and post stress at +25C and hot temp.	45	5	1	50	0	10	Must be in progress at time of package release to production, but completion is not required for release to production.
Preconditioning - Required for surface mount devices	+150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020D for package type; Electrical test pre and post stress at +25°C. MSL-1 @ 260°C	231	15	4	984	0	15	Spares should be properly identified. 77 parts from each lot to be used for HAST, Autoclave, Temp Cycle test.
HAST	+130°C/85% RH for 96 hours. Electrical test pre and post stress at +25°C and hot temp. 1 lot tested at 125C	77	5	4	328	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Unbiased HAST	+130°C/85% RH for 96 hrs	77	5	4	328	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	-65°C to +150°C for 500 cycles. Electrical test pre and post stress at hot temp; 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress. 1 lot tested at 125C	77	5	4	328	0	15	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.